

August 1991

Features

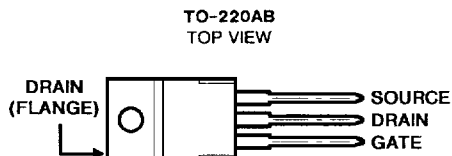
- 2A, 120V and 150V
- $r_{DS(ON)} = 1.75\Omega$
- Design Optimized for 5V Gate Drives
- Can be Driven Directly from QMOS, NMOS, TTL Circuits
- Compatible with Automotive Drive Requirements
- SOA is Power-Dissipation Limited
- Nanosecond Switching Speeds
- Linear Transfer Characteristics
- High Input Impedance
- Majority Carrier Device

Description

The RFP2N12L and RFP2N15L are N-channel enhancement-mode silicon-gate power field-effect transistors specifically designed for use with logic level (5V) driving sources in applications such as programmable controllers, automotive switching, and solenoid drivers. This performance is accomplished through a special gate oxide design which provides full rated conduction at gate biases in the 3V - 5V range, thereby facilitating true on-off power control directly from logic circuit supply voltages.

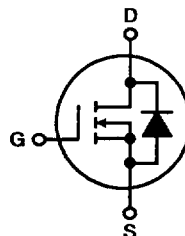
The RFP series types are supplied in the JEDEC TO-220AB plastic package.

Package



Terminal Diagram

N-CHANNEL ENHANCEMENT MODE



Absolute Maximum Ratings ($T_C = +25^\circ\text{C}$) Unless Otherwise Specified

	RFP2N12L	RFP2N15L	UNITS
Drain-Source Voltage	V_{DS} 120	120	V
Drain-Gate Voltage ($R_{GS} = 1\text{M}\Omega$)	V_{DGR} 120	150	V
Continuous Drain Current			
RMS Continuous	I_D 2	2	A
Pulsed Drain Current	I_{DM} 5	5	A
Gate-Source Voltage	V_{GS} ± 10	± 10	V
Maximum Power Dissipation			
$T_C = +25^\circ\text{C}$	P_D 25	25	W
Above $T_C = +25^\circ\text{C}$, Derate Linearly	0.2	0.2	W/ $^\circ\text{C}$
Operating and Storage Junction Temperature Range	T_J, T_{STG} -55 to +150	-55 to +150	$^\circ\text{C}$

Specifications RFP2N12L, RFP2N15L

Electrical Characteristics ($T_C = +25^\circ\text{C}$), Unless Otherwise Specified

CHARACTERISTIC	SYMBOLS	TEST CONDITIONS	LIMITS				UNITS
			RFP2N12L		RFP2N15L		
			MIN	MAX	MIN	MAX	
Drain-Source Breakdown Voltage	BV_{DSS}	$I_D = 1\text{mA}, V_{GS} = 0$	120	-	150	-	V
Gate Threshold Voltage	$V_{GS(th)}$	$V_{GS} = V_{DS}, I_D = 2\text{mA}$	1	2	1	2	V
Zero-Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 100\text{V}$	-	1	-	-	μA
		$V_{DS} = 120\text{V}$	-	-	-	1	μA
		$T_C = +125^\circ\text{C}$ $V_{DS} = 100\text{V}$	-	50	-	-	μA
		$V_{DS} = 120\text{V}$	-	-	-	50	mA
Gate-Source Leakage Current	I_{GSS}	$V_{GS} = \pm 10\text{V}, V_{DS} = 0$	-	100	-	100	nA
Drain-Source On-Voltage	$V_{DS(on)}^*$	$I_D = 1\text{A}, V_{GS} = 5\text{V}$	-	1.75	-	1.75	V
		$I_D = 2\text{A}, V_{GS} = 5\text{V}$	-	4.2	-	4.2	V
Static Drain-Source On Resistance	$r_{DS(on)}^*$	$I_D = 1\text{A}, V_{GS} = 5\text{V}$	-	1.75	-	1.75	Ω
Forward Transconductance	g_{fs}^*	$I_D = 1\text{A}, V_{DS} = 10\text{V}$	800	-	800	-	S (Ω)
Input Capacitance	C_{ISS}	$V_{GS} = 0\text{V}, V_{DS} = 25\text{V}$ $f = 1\text{MHz}$	-	200	-	200	pF
Output Capacitance	C_{OSS}		-	80	-	80	pF
Reverse Transfer Capacitance	C_{RSS}		-	35	-	35	pF
Turn-On Delay Time	$t_{d(on)}$	$I_D = 1\text{A}, V_{DD} = 75\text{V}$ $R_{GEN} = \infty$ $R_{GS} = 6.25\text{V}, V_{GS} = 5\text{V}$	10 (typ)	25	10 (typ)	25	ns
Rise Time	t_r		10 (typ)	45	10 (typ)	45	ns
Turn-Off Delay Time	$t_{d(off)}$		24 (typ)	45	24 (typ)	45	ns
Fail Time	t_f		20 (typ)	25	20 (typ)	25	ns
Thermal Resistance Junction-to-Case	$R_{\theta JC}$		-	5	-	5	$^\circ\text{C/W}$

* Pulsed: Pulse duration = 300 μs max., duty cycle = 2%.

Source-Drain Diode Ratings and Characteristics

CHARACTERISTIC	SYMBOLS	TEST CONDITIONS	LIMITS				UNITS
			RFP2N12L		RFP2N15L		
			MIN	MAX	MIN	MAX	
Diode Forward Voltage	V_{SD}^*	$I_{SD} = -1\text{A}$	-	1.4	-	1.4	V
Diode Reverse Recovery Time	t_{rr}	$I_F = 2\text{A}$ $dI_F/dt = 50\text{A}/\mu\text{s}$	150 (typ)	150 (typ)	150 (typ)	150 (typ)	ns

* Pulse Test: Width $\leq 300\mu\text{s}$, Duty Cycle $\leq 2\%$.

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LOGIC LEVEL
POWER MOSFETS

RFP2N12L, RFP2N15L

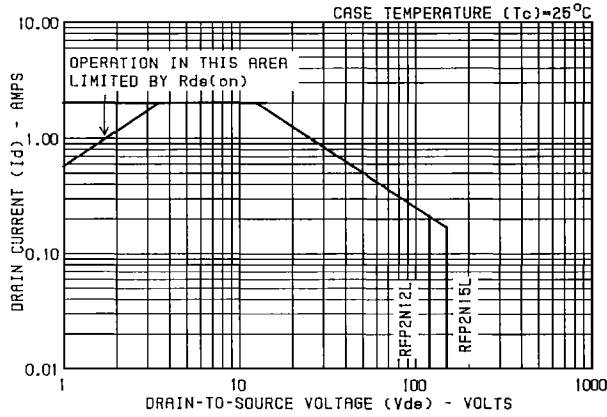


Fig. 1 — Maximum operating areas for all types.

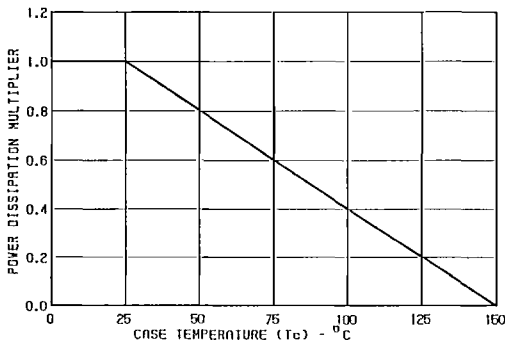


Fig. 2 — Power dissipation vs. case temperature derating curve for all types.

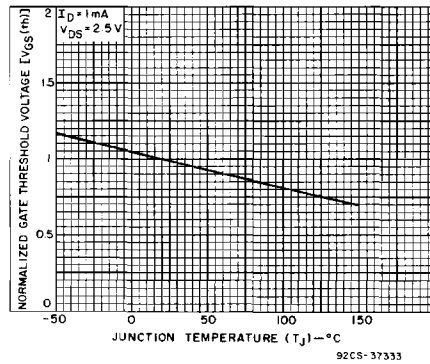


Fig. 3 — Typical normalized gate threshold voltage as a function of junction temperature for all types.

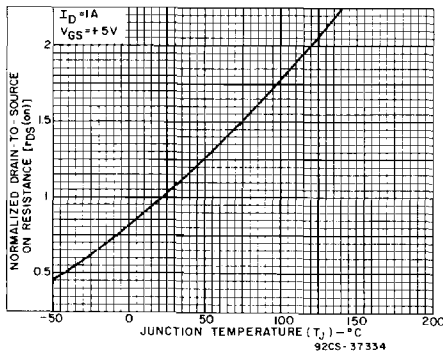


Fig. 4 — Normalized drain-to-source on resistance to junction temperature for all types.

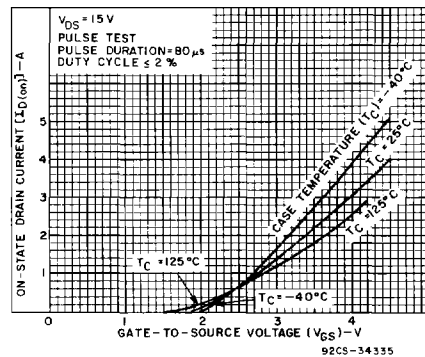


Fig. 5 — Typical transfer characteristics for all types.

RFP2N12L, RFP2N15L

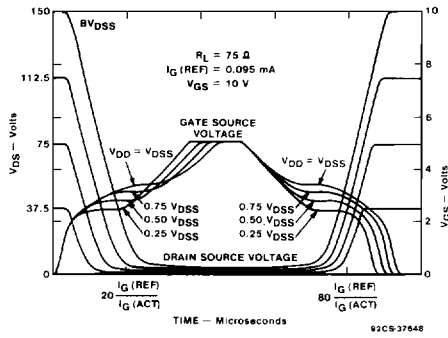


Fig. 6 - Normalized switching waveforms for constant gate-current drive.

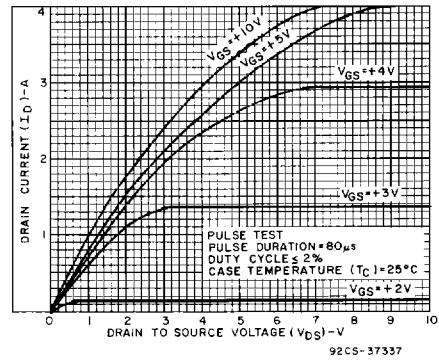


Fig. 7 - Typical saturation characteristics for all types.

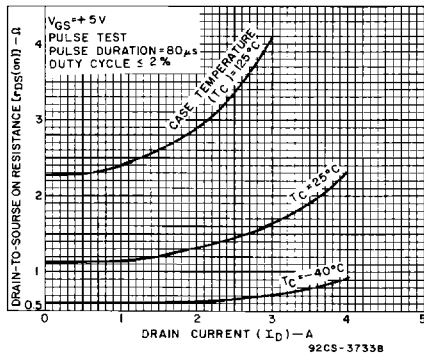


Fig. 8 - Typical drain-to-source on resistance as a function of drain current for all types.

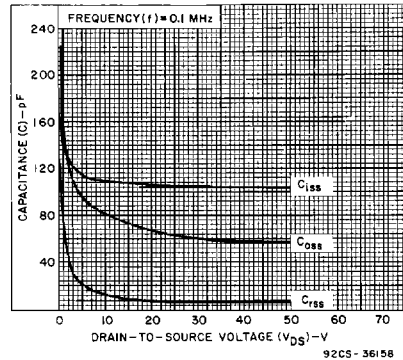


Fig. 9 - Capacitance as a function of drain-to-source voltage for all types.

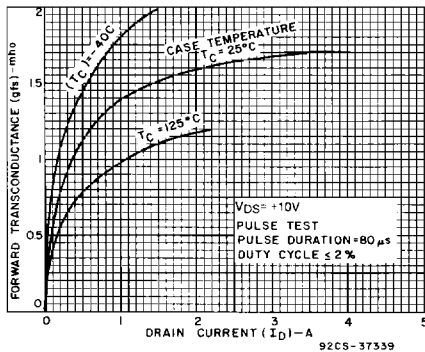


Fig. 10 - Typical forward transconductance as a function of drain current for all types.

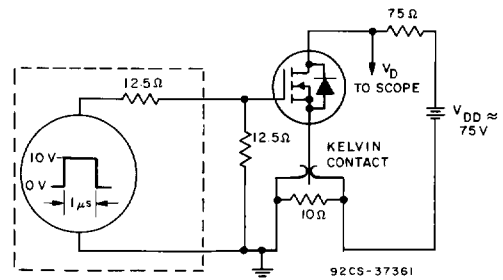


Fig. 11 - Switching Time Test Circuit.

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